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Application/Control No.	Applicant(s)/Patent under Reexamination		
10/644,579	SANCHEZ ET AL.		
Examiner	Art Unit		
Yong S. Chong	1817		

SEARCHED				
Class	Subclass	Date	Examiner	
514	<b>469</b> 	6/15/2005	YSC	
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	Search	1/20/06	YSL	
		8/28/06	YSC	
Ира	ated	3/20/07	Yrc	
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	DATE	EXMR
Inventor (PALM, EAST)	6/15/2005	YSC
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